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Geometrical product specifications (GPS) — Surface texture: Areal —

Part 604:

Nominal characteristics of non- contact (coherence scanning interferometry) instruments

*Spécification géométrique des produits (GPS) — État de surface:
Surfacique —*

*Partie 604: Caractéristiques nominales des instruments sans contact
(à interférométrie par balayage à cohérence)*



Reference number
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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2. www.iso.org/directives

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The committee responsible for this document is ISO/TC 213, *Dimensional and geometrical product specifications and verification*. The document was prepared in collaboration with Technical Committee CEN/TC 290, *Dimensional and geometrical product specifications and verification*.

ISO 25178 consists of the following parts, under the general title *Geometrical product specifications (GPS) — Surface texture: Areal*:

- Part 1: *Indication of surface texture*
- Part 2: *Terms, definitions and surface texture parameters*
- Part 3: *Specification operators*
- Part 6: *Classification of methods for measuring surface texture*
- Part 70: *Physical measurement standards*
- Part 71: *Software measurement standards*
- Part 601: *Nominal characteristics of contact (stylus) instruments*
- Part 602: *Nominal characteristics of non-contact (confocal chromatic probe) instruments*
- Part 603: *Nominal characteristics of non-contact (phase shifting interferometric microscopy) instruments*
- Part 604: *Nominal characteristics of non-contact (coherence scanning interferometry) instruments*
- Part 605: *Nominal characteristics of non-contact (point autofocus probe) instruments*
- Part 606: *Nominal characteristics of non-contact (focus variation) instruments*
- Part 701: *Calibration and measurement standards for contact (stylus) instruments*

The following part is under preparation:

- Part 72: *XML file format x3p*

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Introduction

This part of ISO 25178 is a geometrical product specification (GPS) standard and is to be regarded as a general GPS standard (see ISO/TR 14638). It influences chain link 5 of the chains of standards on roughness profile, waviness profile, primary profile and areal surface texture.

The ISO/GPS Masterplan given in ISO/TR 14638 gives an overview of the ISO/GPS system of which this document is a part. The fundamental rules of ISO/GPS given in ISO 8015 apply to this document and the default decision rules given in ISO 14253-1 apply to specifications made in accordance with this document, unless otherwise indicated.

For more detailed information on the relation of this part of ISO 25178 to other standards and to the GPS matrix model, see [Annex E](#).

This part of ISO 25178 describes the metrological characteristics of coherence scanning interferometric microscopes, designed for the measurement of surface topography maps. For more detailed information on the coherence scanning technique, see [Annex A](#) and [Annex B](#).

NOTE Portions of this document, particularly the informative texts, may describe patented systems and methods. This information is provided only to assist users in understanding the operating principles of coherence scanning interferometry. This document is not intended to establish priority for any intellectual property, nor does it imply a license to any proprietary technologies that may be described herein.